

## Plasma lensing of a laser wakefield accelerated electron bunch

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We report on the first all-optical demonstration of plasma lensing using laser wakefield accelerated electrons in a two-stage setup. The LWFA electron bunch was focused by a second plasma stage without any external fields applied.

Plasma wakefields can provide electrical fields in the order of hundreds of GV/m and thus allow to build compact particle accelerators. However, transportation, shaping and focusing of accelerated particle beams still requires conventional structures which will be much larger than the accelerator itself. As a plasma is used for the acceleration process, it has been shown, that a plasma can be used for focusing the particle bunch as well due to transversal fields inside the plasma wave [1, 2].

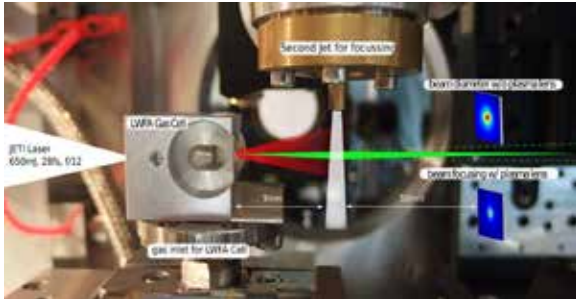


Figure 1: Illustrated photo of experimental setup: the laser pulse, incident from the left, drives an LWFA stage in a mixed-species gas cell, and the generated electron beam expands in vacuum according to its obtained divergence. If the second gas jet is turned on, the remnant and diverged laser pulse preionizes the H<sub>2</sub> gas and the trailing electron beam experiences plasma lensing, which reduces the divergence substantially as observed on a Lanex (Fig 2).

The experiment presented here was conducted at the 40 TW "JETI" Ti:sapphire laser system at the University of Jena, delivering  $\tau = 28$  fs pulses at a central wavelength  $\lambda_0 = 800$  nm with  $E = 650$  mJ on target. The laser pulses were focused by an  $f/12$  off-axis parabolic mirror to a spot size  $w_0^2 = 120$   $\mu\text{m}^2$  (FWHM), resulting in a vacuum peak normalized amplitude of  $a_0 = 2.2$ . The laser focus was aligned to the entrance aperture of a  $z_c = 2.5$  mm long gas cell (acceleration stage) as seen in figure 1. The gas in the gas cell was composed of a 95% He, 5% N<sub>2</sub>

mixture in order to make use of higher-level laser ionization injection [3, 4]. The LWFA stage produced electron bunches up to  $E_{\text{max}} = 130$  MeV with a large energy spread and a total charge of up to 10 pC.

As soon as the focusing stage is turned on, the solid angle covered by the electron beam on the Lanex scintillator screen reduces from 16 mrad<sup>2</sup> to 6 mrad<sup>2</sup> (figure 2) while the total charge of the bunch decreases to 75% of its initial value only (not shown). Thus not only a decrease of the electron divergence but also an increase in electron intensity on the Lanex (a net focusing effect) was measured.

The measured focusing matches the results from particle-in-cell simulations with the EPOCH Code (not shown here).

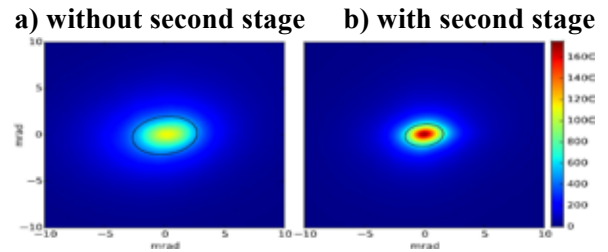


Figure 2: Averaged and center aligned (pointing corrected) beam profile as seen on the Lanex: a) 227 reference shots with the acceleration stage only. b) 175 shots with the second lensing stage. In both pictures the ellipse encloses the standard deviation of a best fit 2D gaussian function to the beam profile. The ellipse reduces its area from 16 mrad<sup>2</sup> (left) to 6 mrad<sup>2</sup> (right) when the focusing stage is turned on.

### References

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